

Michihiro Shintani

List of Publications by Year in descending order

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121
citing authors

#	ARTICLE	IF	CITATIONS
1	Surface-Potential-Based Silicon Carbide Power MOSFET Model for Circuit Simulation. IEEE Transactions on Power Electronics, 2018, 33, 10774-10783.	7.9	23
2	Variation-Aware Hardware Trojan Detection through Power Side-channel. , 2018, , .		18
3	A Variability-Aware Adaptive Test Flow for Test Quality Improvement. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2014, 33, 1056-1066.	2.7	16
4	A high power curve tracer for characterizing full operational range of SiC power transistors. , 2016, , .		9
5	Organic Current Mirror PUF for Improved Stability Against Device Aging. IEEE Sensors Journal, 2020, 20, 7569-7578.	4.7	9
6	Low Cost Recycled FPGA Detection Using Virtual Probe Technique. , 2019, , .		8
7	Feasibility of a low-power, low-voltage complementary organic thin film transistor buskeeper physical unclonable function. Japanese Journal of Applied Physics, 2019, 58, SBBC03.	1.5	7
8	Accurate Recycled FPGA Detection Using an Exhaustive-Fingerprinting Technique Assisted by WID Process Variation Modeling. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2021, 40, 1626-1639.	2.7	7
9	Mechanically and electrically robust metal-mask design for organic CMOS circuits. Japanese Journal of Applied Physics, 2018, 57, 04FL05.	1.5	6
10	Feature Engineering for Recycled FPGA Detection Based on WID Variation Modeling. , 2019, , .		6
11	Recovery-aware bias-stress degradation model for organic thin-film transistors considering drain and gate bias voltages. Japanese Journal of Applied Physics, 2020, 59, SCGG08.	1.5	6
12	OCM-PUF: organic current mirror PUF with enhanced resilience to device degradation. , 2019, , .		5
13	Parameter Extraction Procedure for Surface-Potential-Based SiC MOSFET Model. , 2019, , .		4
14	Measurement and Modeling of Ambient-Air-Induced Degradation in Organic Thin-Film Transistor. IEEE Transactions on Semiconductor Manufacturing, 2020, 33, 216-223.	1.7	4
15	Statistical Extraction of Normally and Lognormally Distributed Model Parameters for Power MOSFETs. IEEE Transactions on Semiconductor Manufacturing, 2020, 33, 150-158.	1.7	4
16	Unsupervised Recycled FPGA Detection Based on Direct Density Ratio Estimation. , 2021, , .		4
17	Accelerating Parameter Extraction of Power MOSFET Models Using Automatic Differentiation. IEEE Transactions on Power Electronics, 2022, 37, 2970-2982.	7.9	3
18	Dominant Model Parameter Extraction for Analyzing Current Imbalance in Parallel Connected SiC MOSFETs. , 2021, , .		3

#	ARTICLE	IF	CITATIONS
19	Efficient worst-case timing analysis of critical-path delay under workload-dependent aging degradation. , 2018, , .		2
20	A Plotter-Based Automatic Measurement and Statistical Characterization of Multiple Discrete Power Devices. , 2018, , .		2
21	Efficient parameter-extraction of SPICE compact model through automatic differentiation. , 2018, , .		2
22	Hardware-Software Co-Design for Decimal Multiplication. Computers, 2021, 10, 17.	3.3	2
23	Influence of Device Parameter Variability on Current Sharing of Parallel-Connected SiC MOSFETs. , 2020, , .		2
24	Path Clustering for Test Pattern Reduction of Variation-Aware Adaptive Path Delay Testing. Journal of Electronic Testing: Theory and Applications (JETTA), 2016, 32, 601-609.	1.2	1
25	A study on statistical parameter modeling of power MOSFET model by principal component analysis. , 2019, , .		1
26	Area-Efficient and Reliable Error Correcting Code Circuit Based on Hybrid CMOS/Memristor Circuit. Journal of Electronic Testing: Theory and Applications (JETTA), 2020, 36, 537-546.	1.2	1
27	LBIST-PUF: An LBIST Scheme Towards Efficient Challenge-Response Pairs Collection and Machine-Learning Attack Tolerance Improvement. , 2020, , .		1
28	Evaluation of thermal couple impedance model of power modules for accurate die temperature estimation up to 200 Å°C. Japanese Journal of Applied Physics, 2022, 61, SC1082.	1.5	1
29	Systematic Unsupervised Recycled Field-Programmable Gate Array Detection. IEEE Transactions on Device and Materials Reliability, 2022, 22, 154-163.	2.0	1
30	Modeling of interelectrode parasitic elements of V-groove SiC MOSFET. Nonlinear Theory and Its Applications IEICE, 2018, 9, 344-357.	0.6	0
31	Electrical and thermal characterization of SiC power MOSFET. , 2018, , .		0
32	Study on High-Accuracy and Low-Cost Recycled FPGA Detection. , 2021, , .		0
33	Unsupervised recycled FPGA detection using exhaustive nearest neighbor residual analysis. Japanese Journal of Applied Physics, 2022, 61, SC1076.	1.5	0